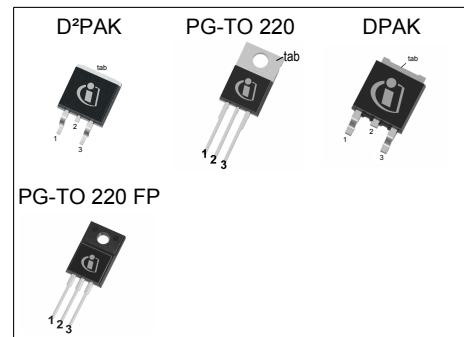


MOSFET

600V CoolMOS™ P6 Power Transistor

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. CoolMOS™ P6 series combines the experience of the leading SJ MOSFET supplier with high class innovation. The offered devices provide all benefits of a fast switching SJ MOSFET while not sacrificing ease of use. Extremely low switching and conduction losses make switching applications even more efficient, more compact, lighter and cooler.



Features

- Increased MOSFET dv/dt ruggedness
- Extremely low losses due to very low FOM $R_{dson} \cdot Q_g$ and E_{oss}
- Very high commutation ruggedness
- Easy to use/drive
- Pb-free plating, Halogen free mold compound
- Qualified for industrial grade applications according to JEDEC (J-STD20 and JESD22)

Potential applications

PFC stages, hard switching PWM stages and resonant switching stages for e.g. PC Silverbox, Adapter, LCD & PDP TV, Lighting, Server, Telecom and UPS.

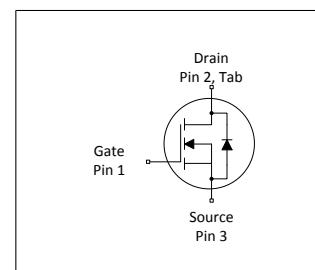


Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	650	V
$R_{DS(on),max}$	380	$\text{m}\Omega$
$Q_{g,typ}$	19	nC
$I_{D,pulse}$	29	A
$E_{oss}@400V$	2.7	μJ
Body diode di/dt	500	$\text{A}/\mu\text{s}$

Type / Ordering Code	Package	Marking	Related Links
IPB60R380P6	PG-TO 263-3	6R380P6	see Appendix A
IPP60R380P6	PG-TO 220-3		
IPD60R380P6	PG-TO 252-3		
IPA60R380P6	PG-TO 220 FullPAK		

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1 Maximum ratings

at $T_j = 25^\circ\text{C}$, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current ¹⁾	I_D	-	-	10.6 6.7	A	$T_C=25^\circ\text{C}$ $T_C=100^\circ\text{C}$
Pulsed drain current ²⁾	$I_{D,\text{pulse}}$	-	-	29	A	$T_C=25^\circ\text{C}$
Avalanche energy, single pulse	E_{AS}	-	-	210	mJ	$I_D=1.8\text{A}; V_{DD}=50\text{V}$; see table 12
Avalanche energy, repetitive	E_{AR}	-	-	0.32	mJ	$I_D=1.8\text{A}; V_{DD}=50\text{V}$; see table 12
Avalanche current, repetitive	I_{AR}	-	-	1.8	A	-
MOSFET dv/dt ruggedness	dv/dt	-	-	100	V/ns	$V_{DS}=0\ldots 400\text{V}$
Gate source voltage (static)	V_{GS}	-20	-	20	V	static;
Gate source voltage (dynamic)	V_{GS}	-30	-	30	V	AC ($f > 1 \text{ Hz}$)
Power dissipation (Non FullPAK) TO-220, TO-252, TO-263	P_{tot}	-	-	83	W	$T_C=25^\circ\text{C}$
Power dissipation (FullPAK) TO-220FP	P_{tot}	-	-	31	W	$T_C=25^\circ\text{C}$
Storage temperature	T_{stg}	-55	-	150	°C	-
Operating junction temperature	T_j	-55	-	150	°C	-
Mounting torque (Non FullPAK) TO-220	-	-	-	60	Ncm	M3 and M3.5 screws
Mounting torque (FullPAK) TO-220FP	-	-	-	50	Ncm	M2.5 screws
Continuous diode forward current	I_S	-	-	9.2	A	$T_C=25^\circ\text{C}$
Diode pulse current ²⁾	$I_{S,\text{pulse}}$	-	-	29	A	$T_C=25^\circ\text{C}$
Reverse diode dv/dt ³⁾	dv/dt	-	-	15	V/ns	$V_{DS}=0\ldots 400\text{V}, I_{SD} \leq I_S, T_j=25^\circ\text{C}$ see table 10
Maximum diode commutation speed	di/ dt	-	-	500	A/ μs	$V_{DS}=0\ldots 400\text{V}, I_{SD} \leq I_S, T_j=25^\circ\text{C}$ see table 10
Insulation withstand voltage for TO-220FP	V_{ISO}	-	-	2500	V	$V_{rms}, T_C=25^\circ\text{C}, t=1\text{min}$

¹⁾ Limited by $T_{j,\text{max}}$. Maximum duty cycle D=0.75

²⁾ Pulse width t_p limited by $T_{j,\text{max}}$

³⁾ Identical low side and high side switch with identical R_G

2 Thermal characteristics

Table 3 Thermal characteristics (Non FullPAK) TO-220

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	1.5	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	leaded
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

Table 4 Thermal characteristics (FullPAK) TO-220FP

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	4	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	80	°C/W	leaded
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

Table 5 Thermal characteristics TO-252, TO-263

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	1.5	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	device on PCB, minimal footprint
Thermal resistance, junction - ambient for SMD version	R_{thJA}	-	35	45	°C/W	Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thickness) copper area for drain connection and cooling. PCB is vertical without air stream cooling.
Soldering temperature, wave & reflow soldering allowed	T_{sold}	-	-	260	°C	reflow MSL1

3 Electrical characteristics

at $T_j=25^\circ\text{C}$, unless otherwise specified

Table 6 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	600	-	-	V	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=1\text{mA}$
Gate threshold voltage	$V_{(\text{GS})\text{th}}$	3.5	4.0	4.5	V	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=0.32\text{mA}$
Zero gate voltage drain current	I_{DSS}	-	-	1 10	μA	$V_{\text{DS}}=600, V_{\text{GS}}=0\text{V}, T_j=25^\circ\text{C}$ $V_{\text{DS}}=600, V_{\text{GS}}=0\text{V}, T_j=150^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	-	100	nA	$V_{\text{GS}}=20\text{V}, V_{\text{DS}}=0\text{V}$
Drain-source on-state resistance	$R_{\text{DS}(\text{on})}$	-	0.342 0.889	0.380 -	Ω	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=3.8\text{A}, T_j=25^\circ\text{C}$ $V_{\text{GS}}=10\text{V}, I_{\text{D}}=3.8\text{A}, T_j=150^\circ\text{C}$
Gate resistance	R_{G}	-	7.8	-	Ω	$f=1\text{MHz}$, open drain

Table 7 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	877	-	pF	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=100\text{V}, f=1\text{MHz}$
Output capacitance	C_{oss}	-	42	-	pF	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=100\text{V}, f=1\text{MHz}$
Effective output capacitance, energy related ¹⁾	$C_{\text{o(er)}}$	-	33	-	pF	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\ldots400\text{V}$
Effective output capacitance, time related ²⁾	$C_{\text{o(tr)}}$	-	135	-	pF	$I_{\text{D}}=\text{constant}, V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\ldots400\text{V}$
Turn-on delay time	$t_{\text{d(on)}}$	-	12	-	ns	$V_{\text{DD}}=400\text{V}, V_{\text{GS}}=13\text{V}, I_{\text{D}}=4.8\text{A}, R_{\text{G}}=3.4\Omega$; see table 11
Rise time	t_{r}	-	6	-	ns	$V_{\text{DD}}=400\text{V}, V_{\text{GS}}=13\text{V}, I_{\text{D}}=4.8\text{A}, R_{\text{G}}=3.4\Omega$; see table 11
Turn-off delay time	$t_{\text{d(off)}}$	-	33	-	ns	$V_{\text{DD}}=400\text{V}, V_{\text{GS}}=13\text{V}, I_{\text{D}}=4.8\text{A}, R_{\text{G}}=3.4\Omega$; see table 11
Fall time	t_{f}	-	7	-	ns	$V_{\text{DD}}=400\text{V}, V_{\text{GS}}=13\text{V}, I_{\text{D}}=4.8\text{A}, R_{\text{G}}=3.4\Omega$; see table 11

Table 8 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	5.4	-	nC	$V_{\text{DD}}=400\text{V}, I_{\text{D}}=4.8\text{A}, V_{\text{GS}}=0 \text{ to } 10\text{V}$
Gate to drain charge	Q_{gd}	-	7	-	nC	$V_{\text{DD}}=400\text{V}, I_{\text{D}}=4.8\text{A}, V_{\text{GS}}=0 \text{ to } 10\text{V}$
Gate charge total	Q_{g}	-	19	-	nC	$V_{\text{DD}}=400\text{V}, I_{\text{D}}=4.8\text{A}, V_{\text{GS}}=0 \text{ to } 10\text{V}$
Gate plateau voltage	V_{plateau}	-	6.1	-	V	$V_{\text{DD}}=400\text{V}, I_{\text{D}}=4.8\text{A}, V_{\text{GS}}=0 \text{ to } 10\text{V}$

¹⁾ $C_{\text{o(er)}}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V

²⁾ $C_{\text{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Table 9 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.9	-	V	$V_{GS}=0V$, $I_F=4.8A$, $T_J=25^\circ C$
Reverse recovery time	t_{rr}	-	232	-	ns	$V_R=400V$, $I_F=4.8A$, $di_F/dt=100A/\mu s$; see table 10
Reverse recovery charge	Q_{rr}	-	2.1	-	μC	$V_R=400V$, $I_F=4.8A$, $di_F/dt=100A/\mu s$; see table 10
Peak reverse recovery current	I_{rrm}	-	17	-	A	$V_R=400V$, $I_F=4.8A$, $di_F/dt=100A/\mu s$; see table 10

4 Electrical characteristics diagrams

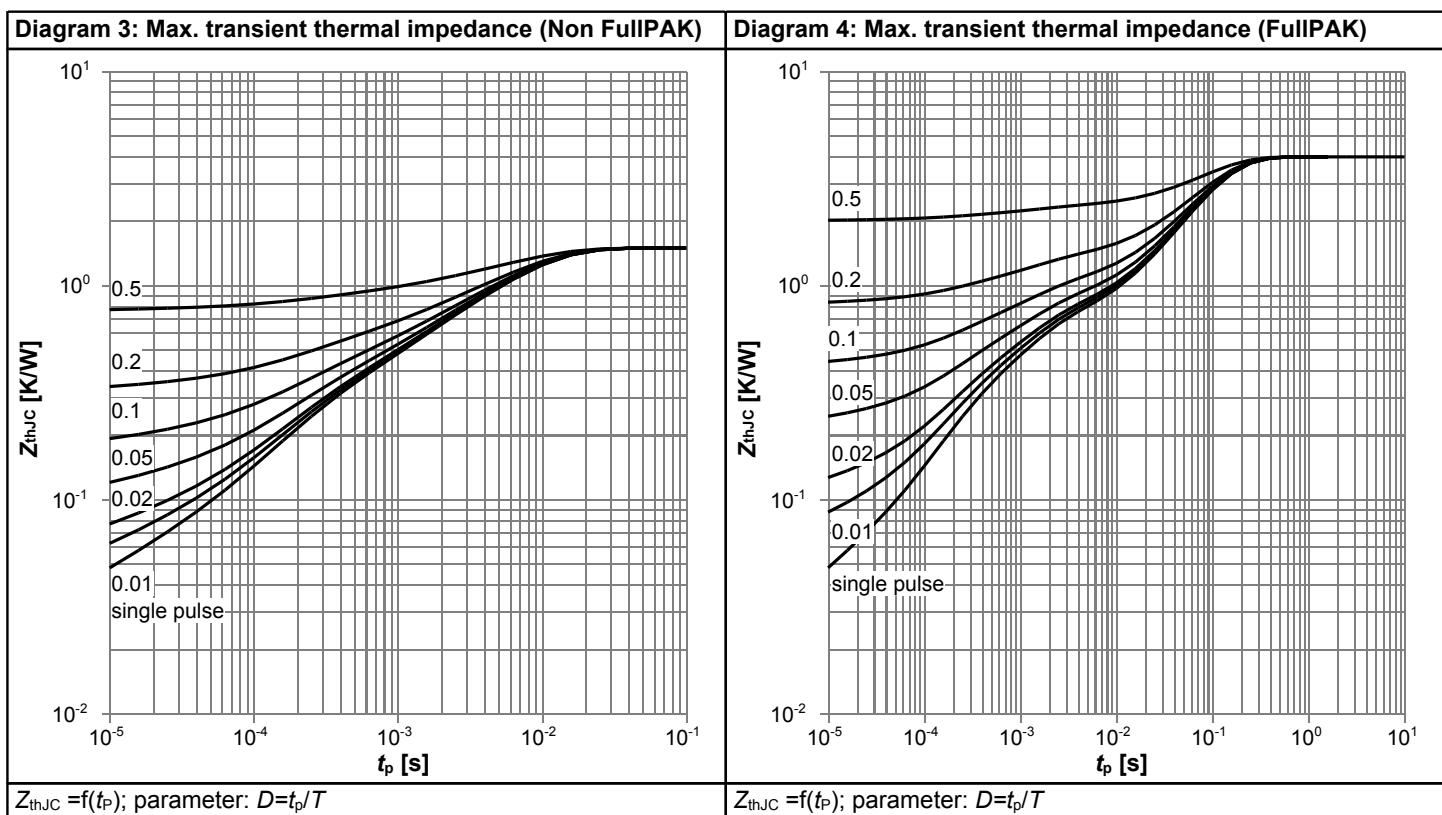
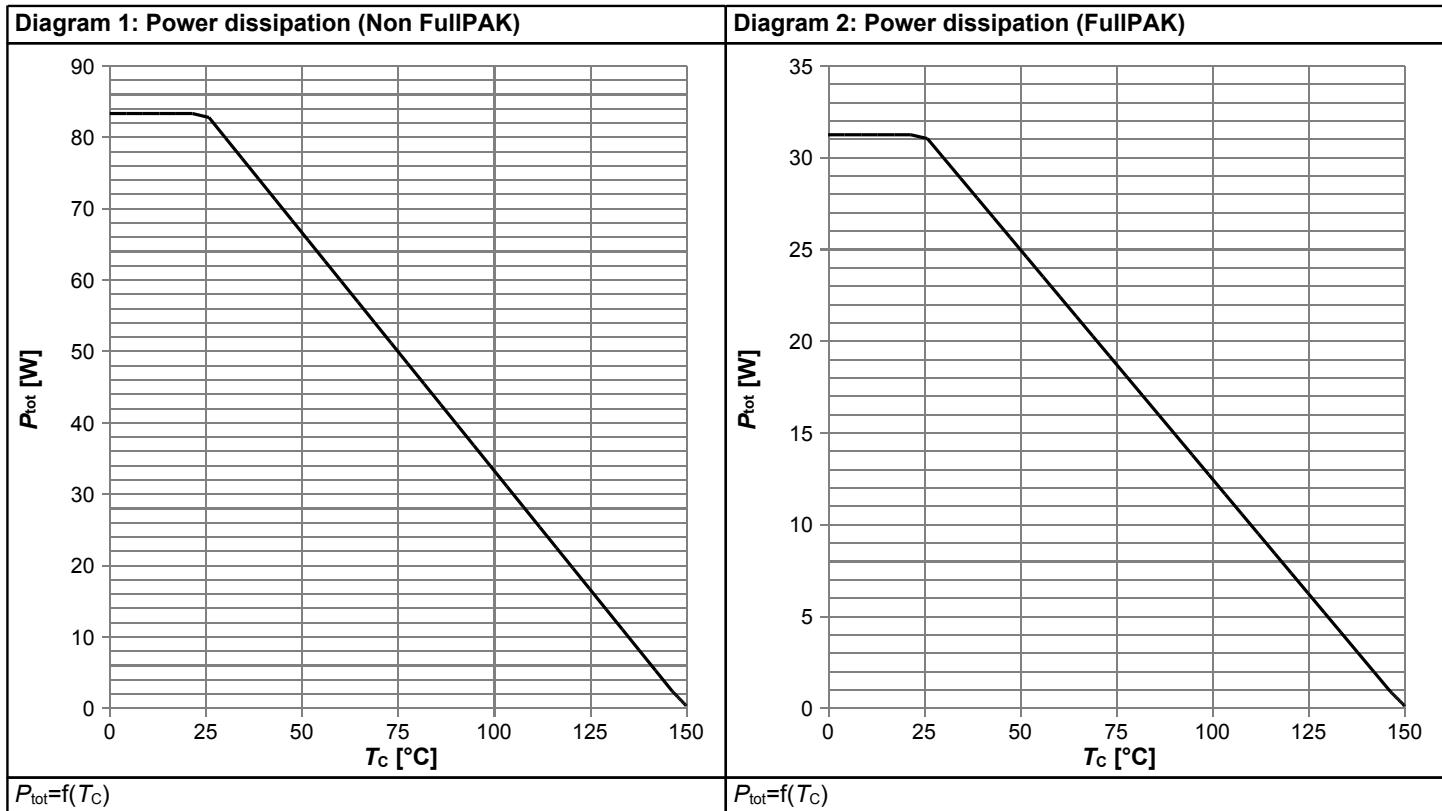
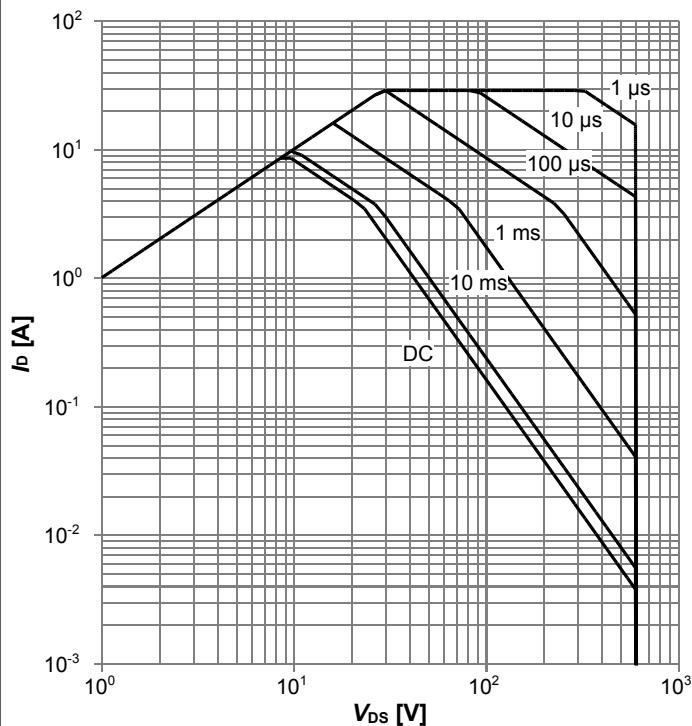
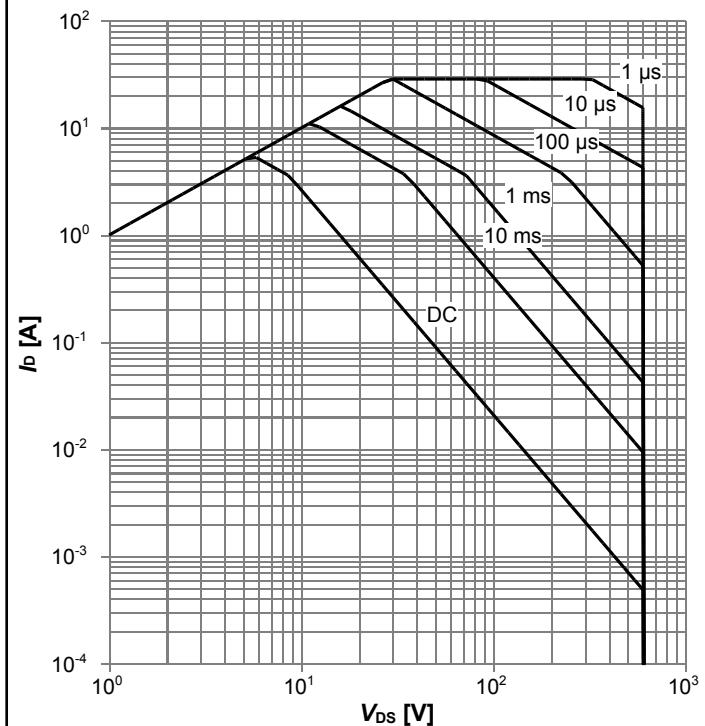


Diagram 5: Safe operating area (Non FullPAK)



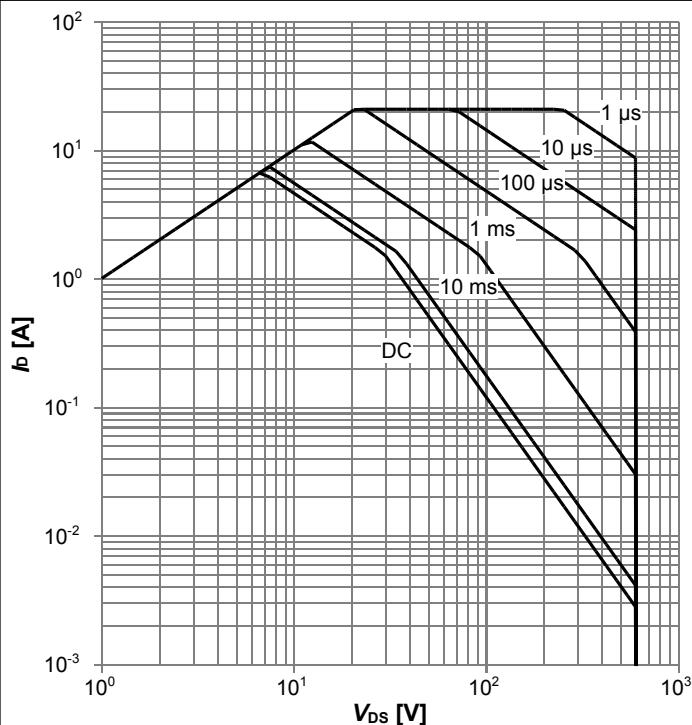
$I_D=f(V_{DS})$; $T_C=25\text{ }^\circ\text{C}$; $D=0$; parameter: t_p

Diagram 6: Safe operating area (FullPAK)



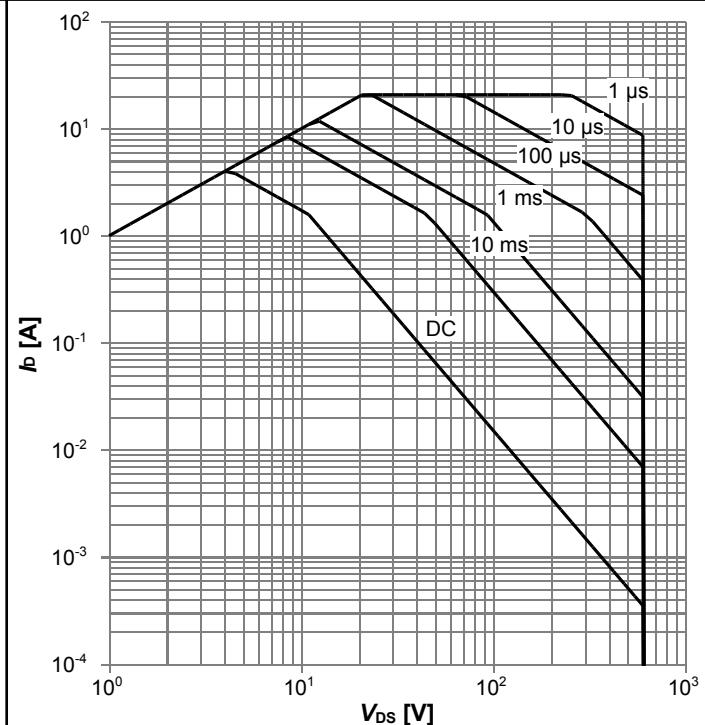
$I_D=f(V_{DS})$; $T_C=25\text{ }^\circ\text{C}$; $D=0$; parameter: t_p

Diagram 7: Safe operating area (Non FullPAK)



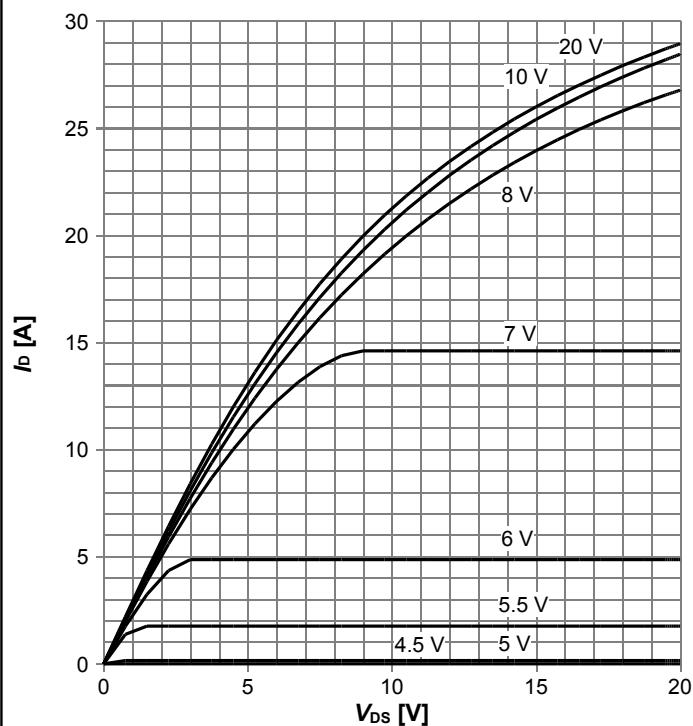
$I_D=f(V_{DS})$; $T_C=80\text{ }^\circ\text{C}$; $D=0$; parameter: t_p

Diagram 8: Safe operating area (FullPAK)



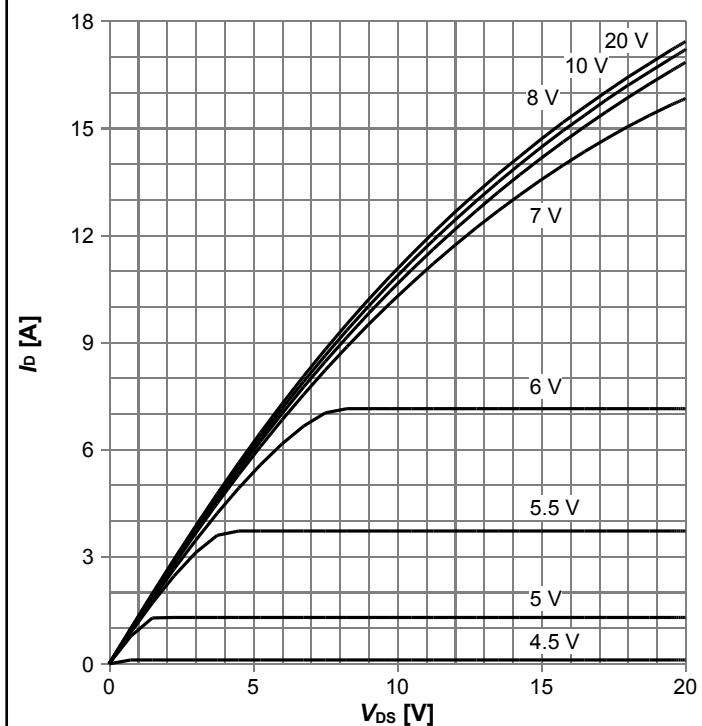
$I_D=f(V_{DS})$; $T_C=80\text{ }^\circ\text{C}$; $D=0$; parameter: t_p

Diagram 9: Typ. output characteristics



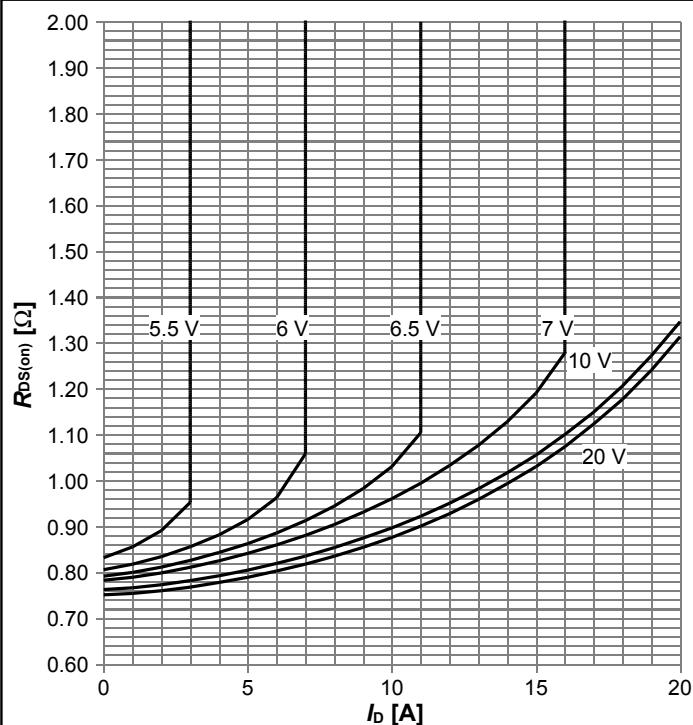
$I_D=f(V_{DS})$; $T_j=25\text{ }^\circ\text{C}$; parameter: V_{GS}

Diagram 10: Typ. output characteristics



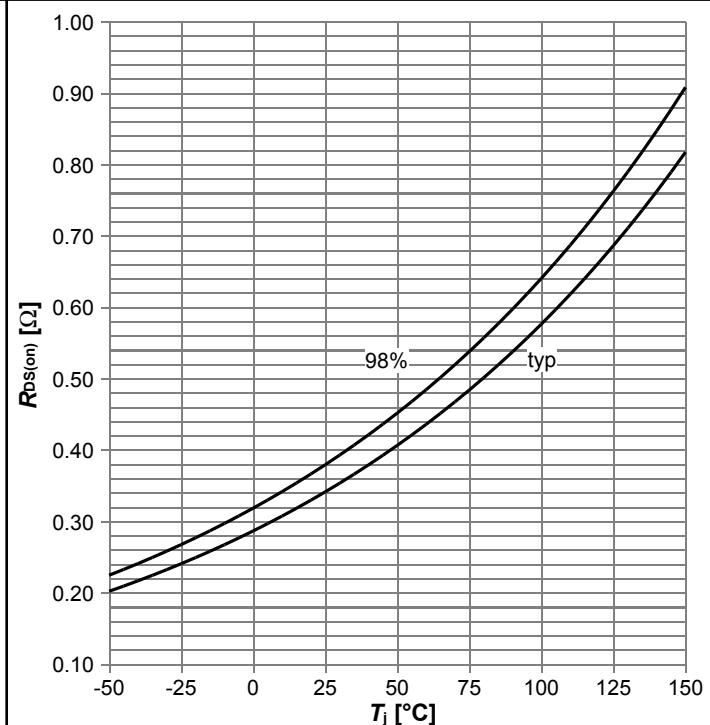
$I_D=f(V_{DS})$; $T_j=125\text{ }^\circ\text{C}$; parameter: V_{GS}

Diagram 11: Typ. drain-source on-state resistance



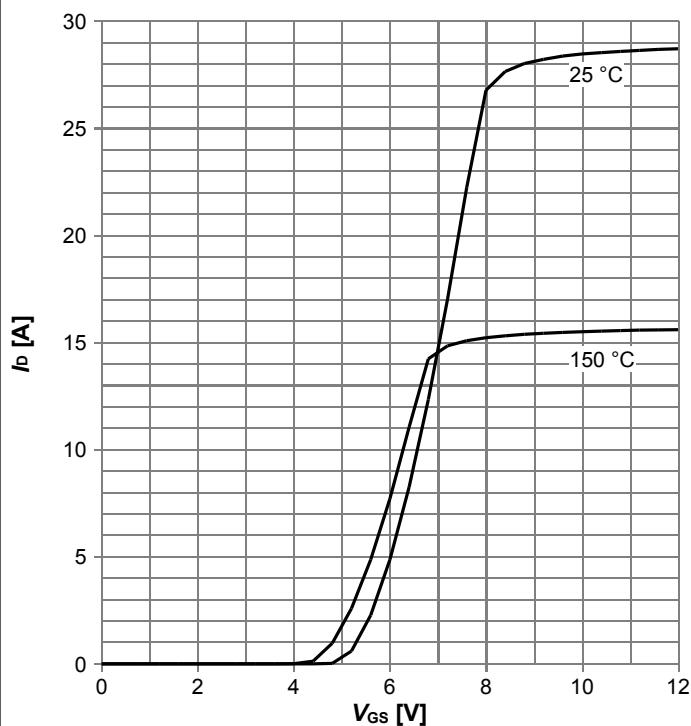
$R_{DS(on)}=f(I_D)$; $T_j=125\text{ }^\circ\text{C}$; parameter: V_{GS}

Diagram 12: Drain-source on-state resistance



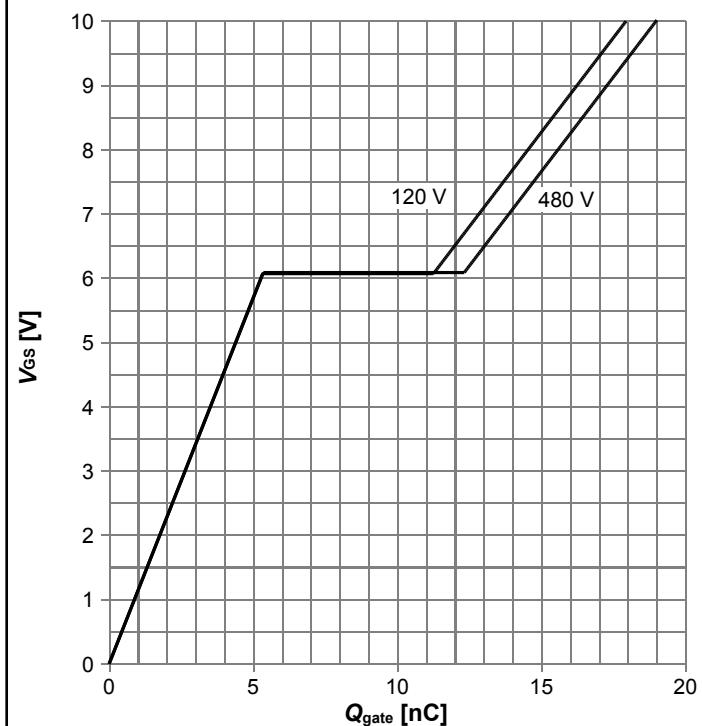
$R_{DS(on)}=f(T_j)$; $I_D=3.8\text{ A}$; $V_{GS}=10\text{ V}$

Diagram 13: Typ. transfer characteristics



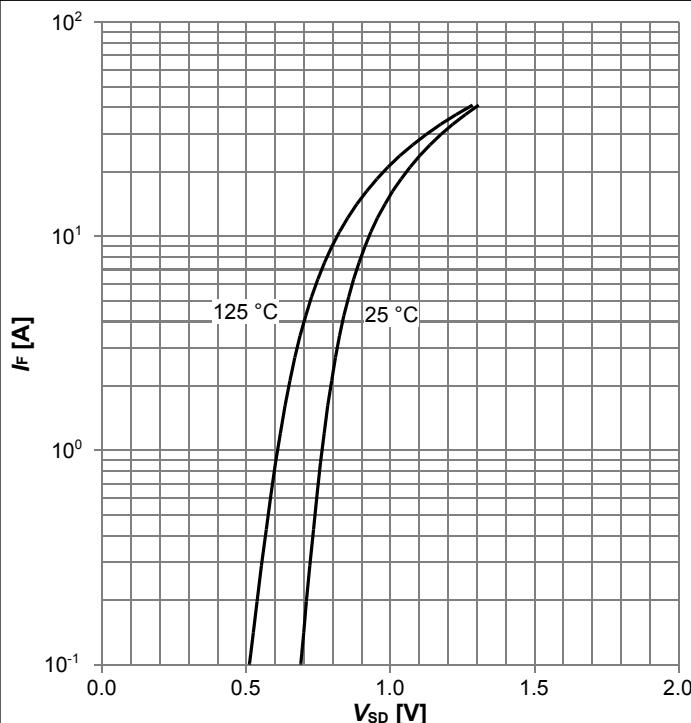
$I_D=f(V_{GS})$; $V_{DS}=20\text{V}$; parameter: T_j

Diagram 14: Typ. gate charge



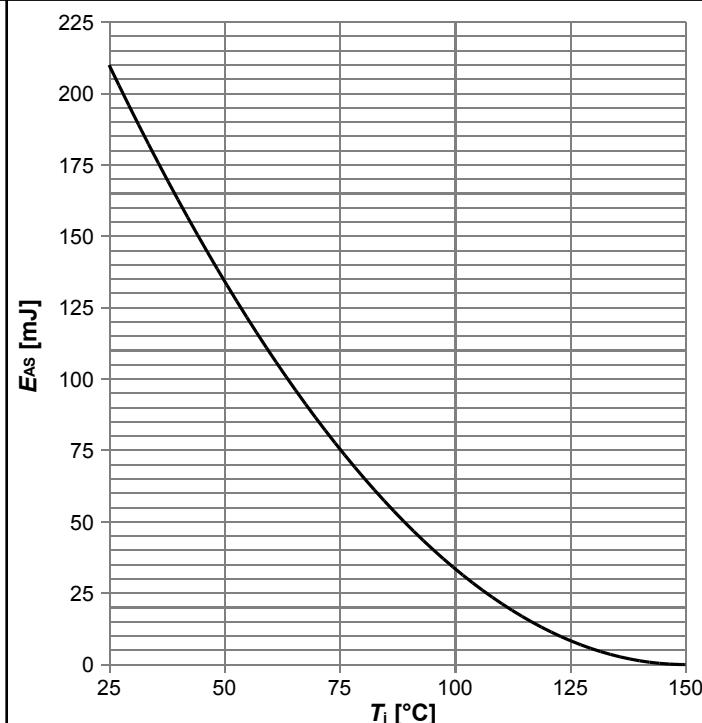
$V_{GS}=f(Q_{gate})$; $I_D=4.8\text{ A}$ pulsed; parameter: V_{DD}

Diagram 15: Forward characteristics of reverse diode



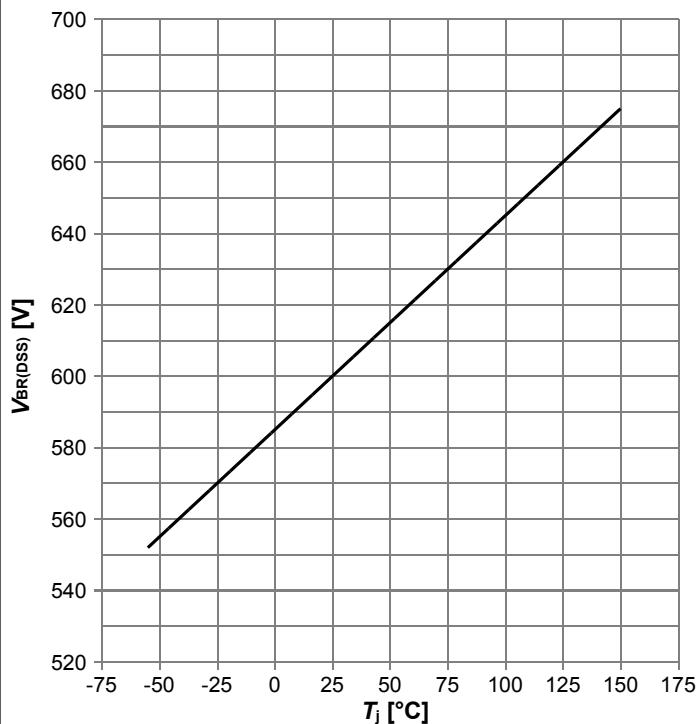
$I_F=f(V_{SD})$; parameter: T_j

Diagram 16: Avalanche energy



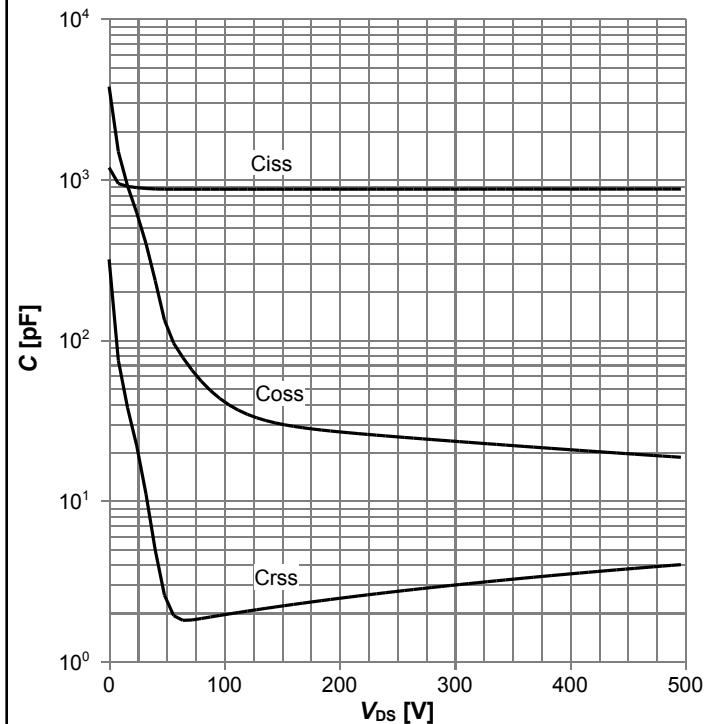
$E_{AS}=f(T_j)$; $I_D=1.8\text{ A}$; $V_{DD}=50\text{ V}$

Diagram 17: Drain-source breakdown voltage



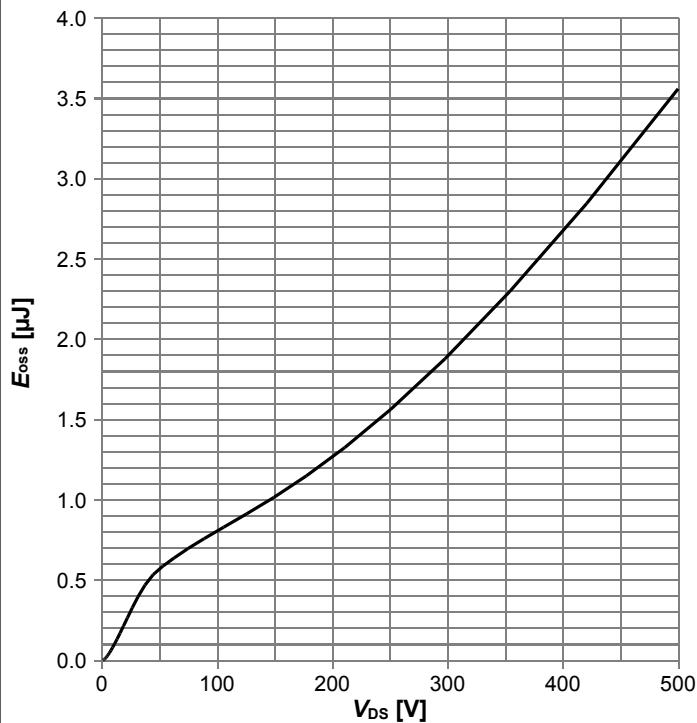
$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$

Diagram 18: Typ. capacitances



$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

Diagram 19: Typ. Coss stored energy



$E_{oss} = f(V_{DS})$

5 Test Circuits

Table 10 Diode characteristics

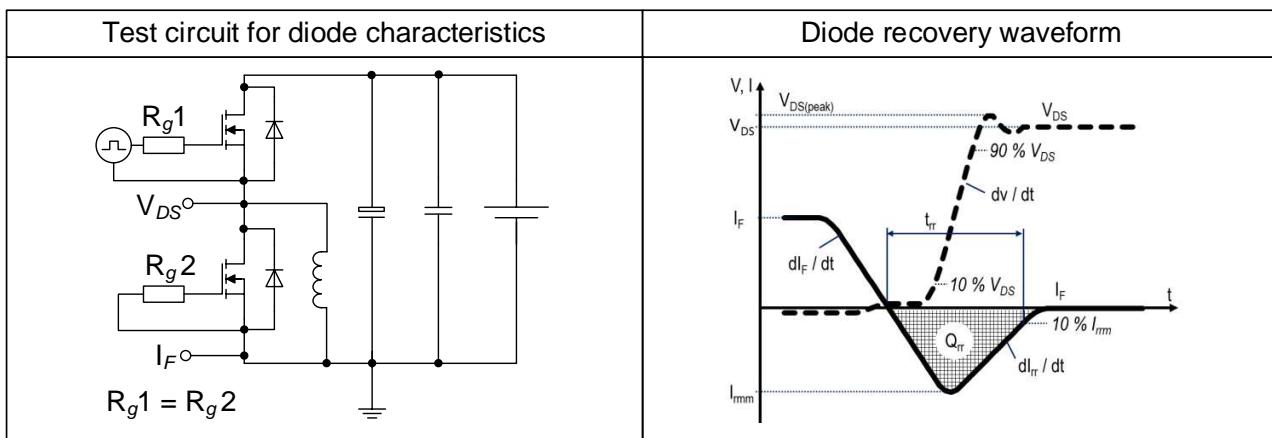


Table 11 Switching times

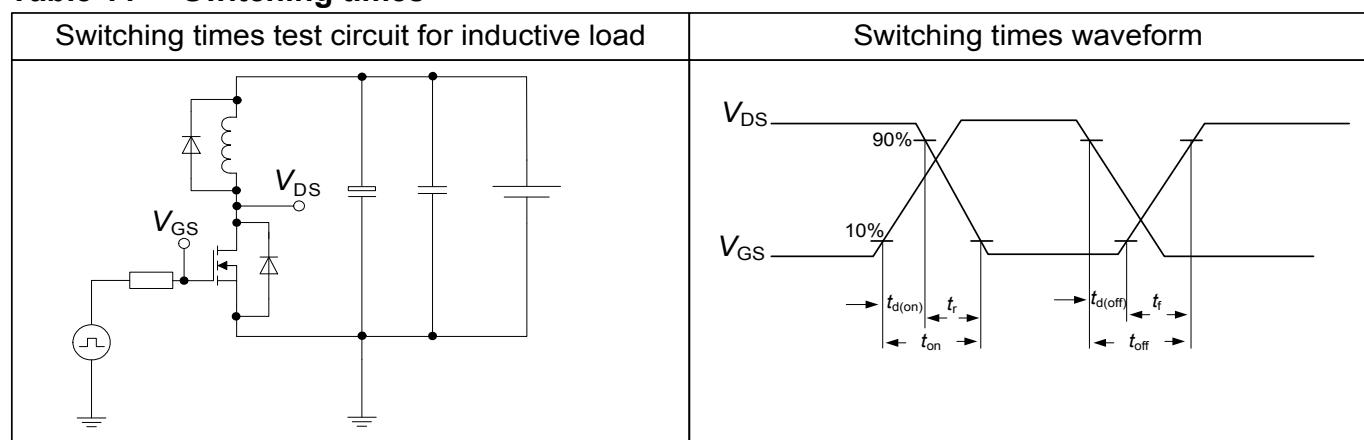
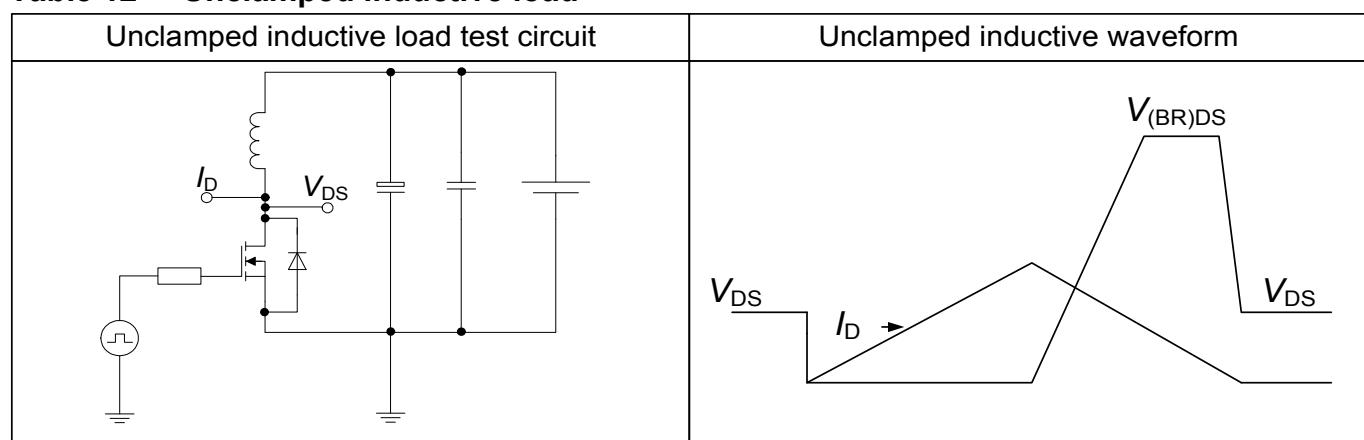


Table 12 Unclamped inductive load



6 Package Outlines

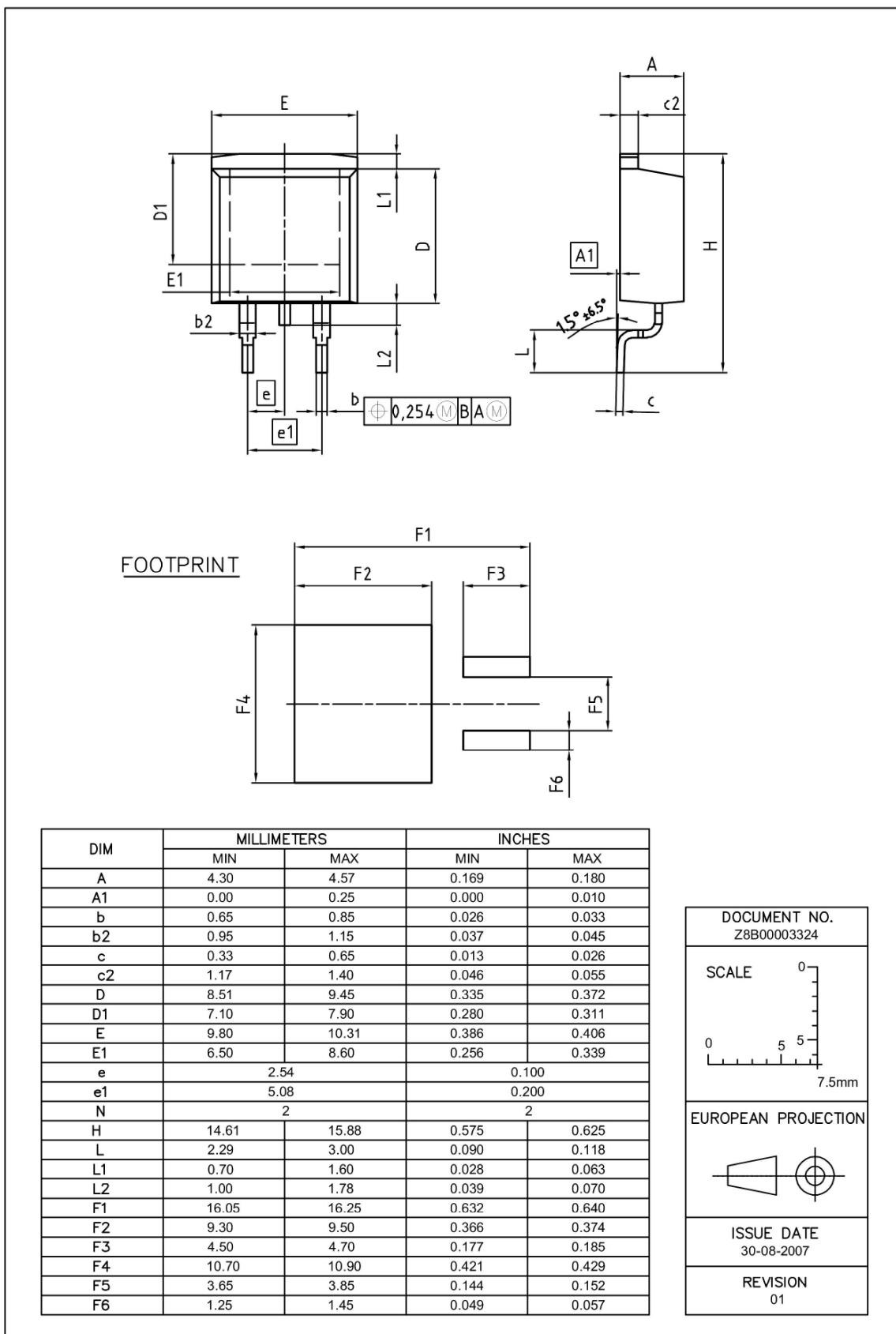


Figure 1 Outline PG-T0 263-3, dimensions in mm/inches

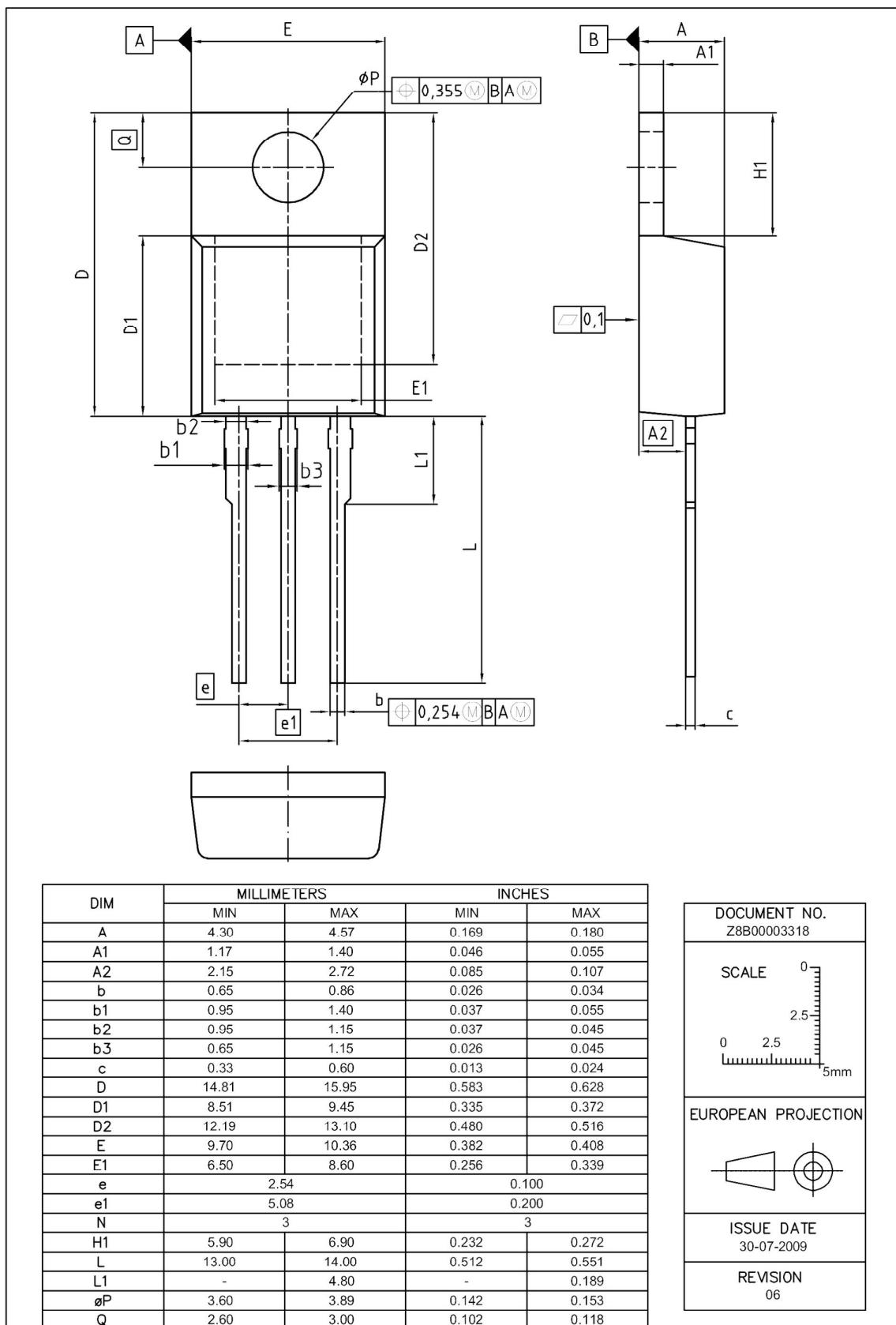


Figure 2 Outline PG-T0 220-3, dimensions in mm/inches

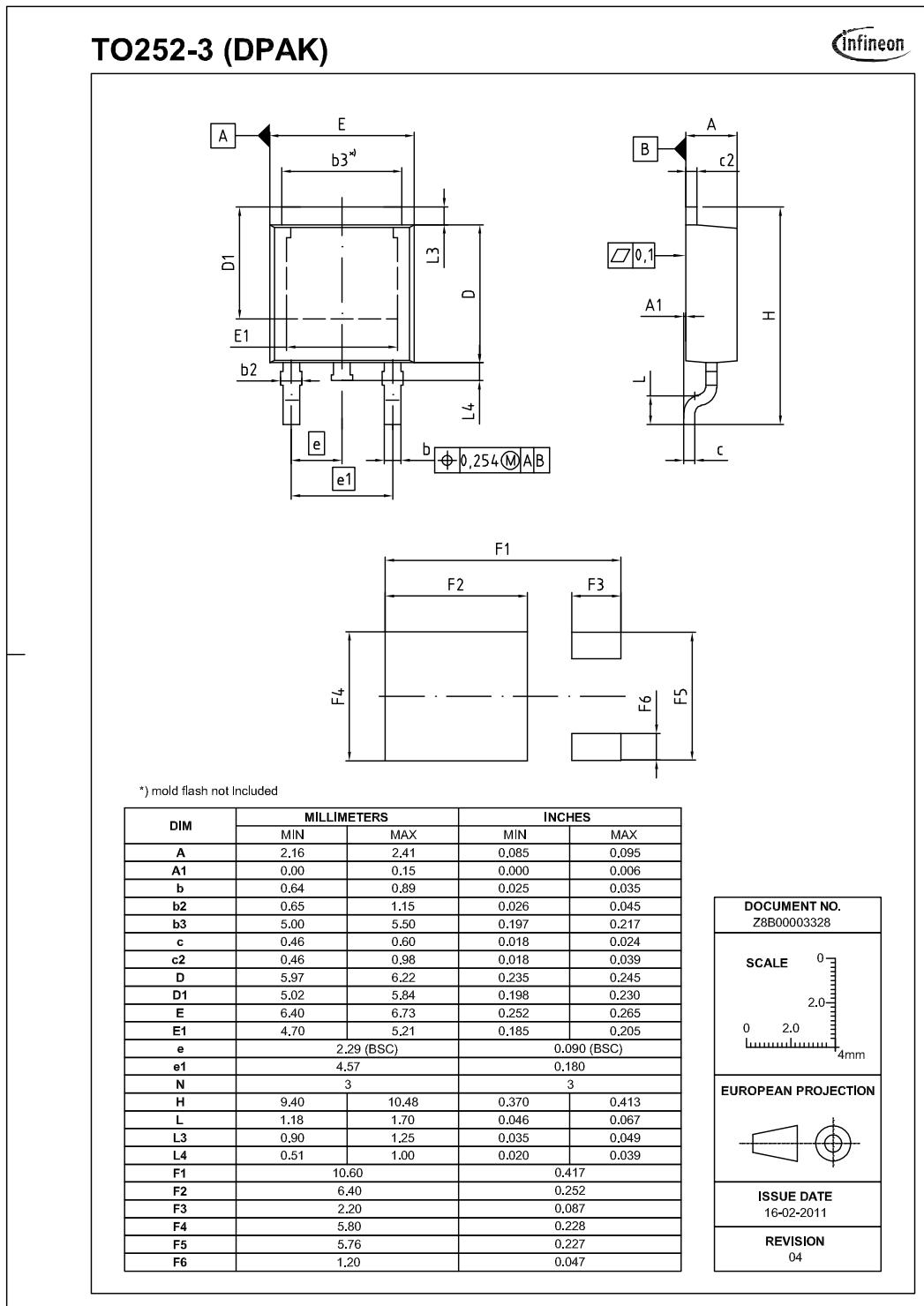


Figure 3 Outline PG-TO 252-3, dimensions in mm/inches

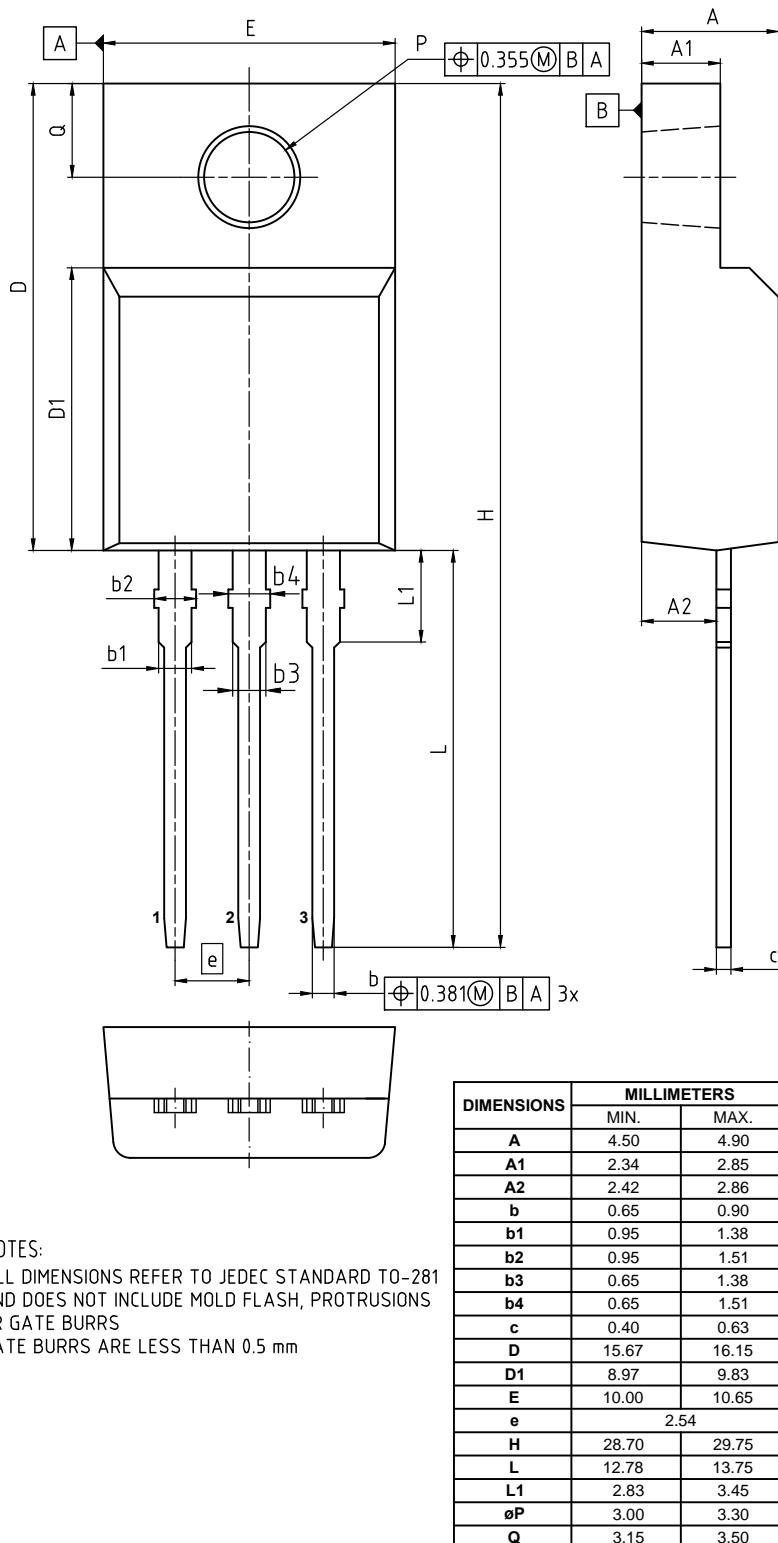


Figure 4 Outline PG-T0 220 FullPAK, dimensions in mm/inches

7 Appendix A

Table 13 Related Links

- **IFX CoolMOS™ P6 Webpage:** www.infineon.com
- **IFX CoolMOS™ P6 application note:** www.infineon.com
- **IFX CoolMOS™ P6 simulation model:** www.infineon.com
- **IFX Design tools:** www.infineon.com

Revision History

IPB60R380P6, IPP60R380P6, IPD60R380P6, IPA60R380P6

Revision: 2017-08-22, Rev. 2.3

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2013-12-05	Release of final version
2.1	2013-12-05	Release of multi-package datasheet
2.2	2015-07-10	PG-T0 263 package added
2.3	2017-08-22	Updated TO220 Full PAK package drawing on page 16

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